

# **60V N-Channel Trench MOSFET**

## **General Description**

- Trench Power SGT technology
- Very low on-resistance R<sub>DS(ON)</sub>
- Low Gate Charge
- Excellent Gate Charge x R<sub>DS(ON)</sub> Product

### **Applications**

• High Frequency Switching and Synchronous Rectification

### **Product Summary**

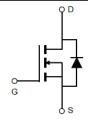
 $V_{DS}$  60V  $I_{D}$  (at  $V_{GS}$ =10V) 60A

 $R_{DS(ON)}$  (at  $V_{GS} = 10V$ ) <  $9m\Omega$ 

100% UIS Tested







Part Number	Package Type	Form	Marking
TSP12N06A	TO-220	Tube	P12N06A

# Absolute Maximum Ratings (T<sub>A</sub> =25°C unless otherwise noted)

- <sub>C</sub> =25°C	V <sub>DS</sub>	60 ±20	V
- <sub>C</sub> =25°C	V <sub>GS</sub>	±20	V
<sub>C</sub> =25°C			1
		60	^
<sub>C</sub> =100°C	I <sub>D</sub>	36	A
Pulsed Drain Current A		240	А
Avalanche Current A		36	А
L =0.3mH <sup>A</sup>	E <sub>AS</sub>	65	mJ
<sub>C</sub> =25°C	D	56.5	W
<sub>C</sub> =100°C	P <sub>D</sub>	44	W
Junction and Storage Temperature Range		-55 to 175	°C
	= 0.3mH A = = 25°C = = 100°C	I <sub>DM</sub> I <sub>AS</sub> = 0.3mH A E <sub>AS</sub> = 25°C  = 100°C  P <sub>D</sub>	I <sub>DM</sub> 240  I <sub>AS</sub> 36  -=0.3mH A E <sub>AS</sub> 65  -=25°C -=100°C 56.5  44

#### **Thermal Characteristics**

Parameter		Symbol	Maximum	Units
Maximum Junction-to-Case	Steady-State	$R_{\Theta JC}$	1.7	°C/W
Maximum Junction-to-Ambient	Steady-State	$R_{\Theta JA}$	50	3C/VV



Electric	al Characteristics(T <sub>J</sub> =25°C un	less otherwise r	noted)				
C: mala al	Development	Conditions		Value			
Symbol	Parameter			Min	Тур	Max	Units
STATIC P	ARAMETERS			_		_	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		60			٧
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	T <sub>J</sub> =25°C T <sub>J</sub> =125°C			1 100	μΑ
I <sub>GSS</sub>	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$				±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$				4	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A			6.5	9	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A			85		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V				1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current B				46	Α	
DYNAMIC	PARAMETERS					•	
C <sub>iss</sub>	Input Capacitance				2455		
C <sub>oss</sub>	Output Capacitance	$V_{GS} = 0V, V_{DS} = 30V, f = 1MH_Z$			240		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	7			34		
SWITCHIN	IG PARAMETERS	•					
$Q_g$	Total Gate Charge				45		
$Q_{gs}$	Gate Source Charge	V <sub>GS</sub> =10V,V <sub>DS</sub> =30V, I <sub>D</sub> =20A			13.5		nC
$Q_{gd}$	Gate Drain Charge				11.5		
t <sub>D(on)</sub>	Turn-On Delay Time	$V_{GS} = 10V, V_{DS} = 30V, I_{D} = 20A,$ $R_{G} = 3\Omega$			8		
t <sub>r</sub>	Turn-On Rise Time				3		ns
$T_{D(off)}$	Turn-Off Delay Time				25		
t <sub>f</sub>	Turn-Off Fall Time				4		
t <sub>rr</sub>	Body Diode Reverse Recovery Time	1 204 4:/4- 5004/			25		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, di/dt =500A/μs			110		nC

- A. Single pulse width limited by maximum junction temperature.
- B. The maximum current rating is package limited.
- C. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$  =175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.



## **Typical Characteristics** $T_J = 25^{\circ}C$ , unless otherwise noted

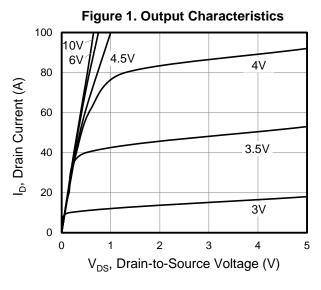
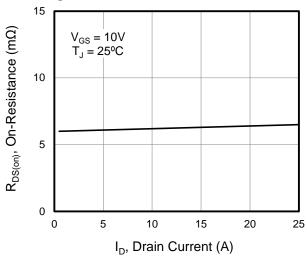


Figure 3. On-Resistance vs. Drain Current



Ontogodiage (V) as a solution of the solution

Q<sub>g</sub>, Total Gate Charge (nC)

Figure 5. Gate Charge

Figure 2. Transfer Characteristics  $V_{DS} = 5V$   $V_{DS} = 5V$ 

Figure 4. Capacitance

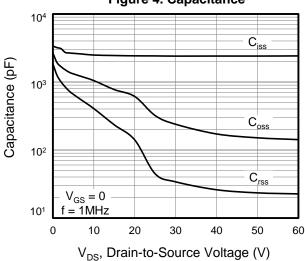
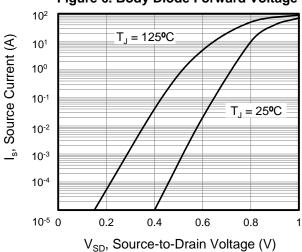
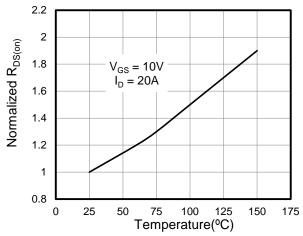


Figure 6. Body Diode Forward Voltage



# **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted



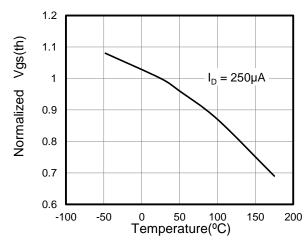
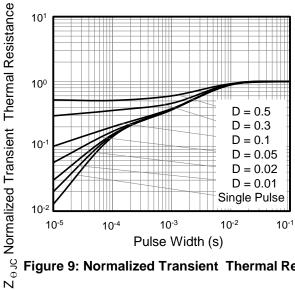


Figure 7: On-Resistance vs. Junction Temperature





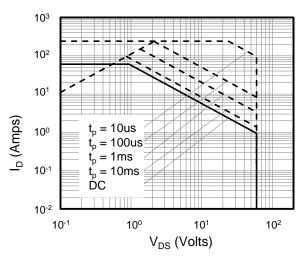


Figure 9: Normalized Transient Thermal Resistance

Figure 10: Safe Operating Area



Figure A: Gate Charge Test Circuit and Waveform

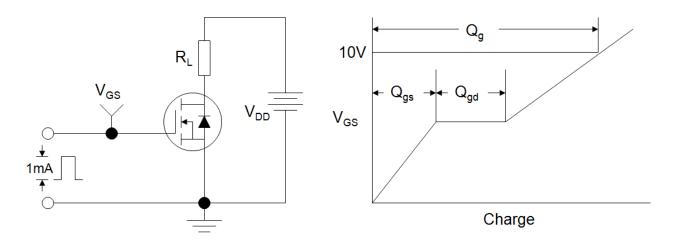


Figure B: Resistive Switching Test Circuit and Waveform

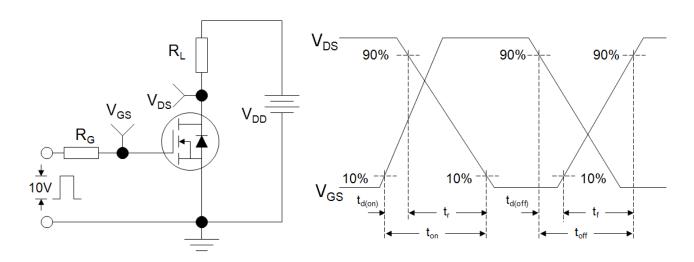
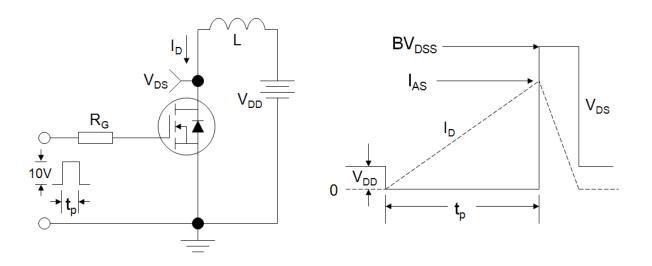
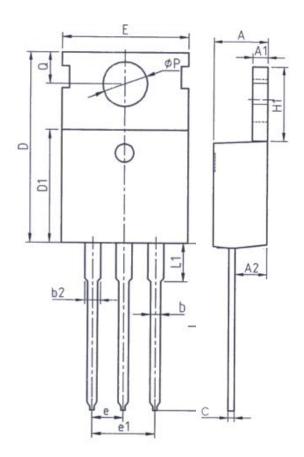


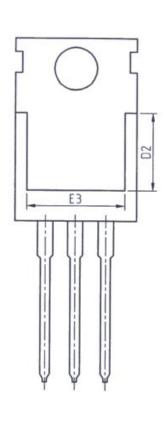
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





**TO-220** 





Unit: mm				
Symbol	Min.	Max.		
Α	4. 37	4. 77		
A1	1. 25	1. 45		
A2	2. 20	2. 60		
b	0. 70	0. 95		
b2	1. 17	1. 47		
С	0. 40	0. 65		
D	15. 10	16. 10		
D1	8. 80	9. 40		
D2	5. 50	_		

Unit: mm				
Symbol	Min.	Max.		
E	9. 70	10. 30		
E3	7. 00	_		
е	2. 54BSC			
e1	5. 08BSC			
H1	6. 25	6. 85		
L	12. 75	13.80		
L1	_	3. 40		
Р	3. 40	3. 80		
Q	2. 60	3.00		



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